

Search Notes

Application/Control No.

10/705,818

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	7/10/2006	CH
455	411	7/10/2006	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	7/10/2006	CH
IDS	7/10/2006	CH
Combined Text Search: class 455/411 + charge + value + entity	7/11/2006	CH